

 <p>OIE INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p>			Docket: 1011-57087		App: 09/385,666		
			Applicant: Suaya and Gabillet				
			Filed: August 26, 1999		Art Unit: 2858		
U.S. PATENT DOCUMENTS							
Init.*		Number	Date	Name	Class	Sub	Filed
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T.P.		McGaughy et al., "A Simple Method for On-Chip, Sub-Femto Farad Interconnect Capacitance Measurement", IEEE Electron Device Letters, Vol. 18. No, 1, January 1997					
EXAMINER: <i>Thai Phan</i>			DATE <i>u/02/02</i>				
<p>*Examiner: Initial if considered, whether or not in conformance with MPEP 609; draw line through cite if not in conformance and not considered. Send copy.</p>							

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